

**PATENT NUMBER and
ISSUE DATE**

U.S. UTILITY Patent Application

APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10082431	02/22/2002	324	73	2858	<i>N.Lc</i>

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**CONTINUING DATA VERIFIED:

None a4

** FOREIGN APPLICATIONS VERIFIED:

None a4

PG-PUB	DO NOT PUBLISH <input checked="" type="checkbox"/>	RESCIND <input type="checkbox"/>
Foreign priority claimed 35 USC 119 conditions met		<input type="checkbox"/> yes <input checked="" type="checkbox"/> no <input type="checkbox"/> yes <input checked="" type="checkbox"/> no
Verified and Acknowledged Examiner's initials <i>a4</i>		
ATTORNEY DOCKET NO SUN-P6557		
TITLE : Integrated electromigration length effect testing method and apparatus U.S. DEPT. OF COMM./PAT. & TM-PTO-436L (Rev. 12-94)		

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
		Total Claims	Print Claim for 0.0
Assistant Examiner <i>Amy H. C.</i>		DRAWING	
Amount Due	Date Paid	Sheets Drawn	Fig. Drawn
Primary Examiner		Print Fig.	
TERMINAL		PREPARED FOR ISSUE	
DISCLAIMER		Application Examiner	
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